



Poworld  
Company

# Semiconductor Testing Solutions

Building on the Past, Shaping  
the Future

Presented by  
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January  
16, 2026

**POWORLD  
ELECTRONIC**

# About Poworld Company

01

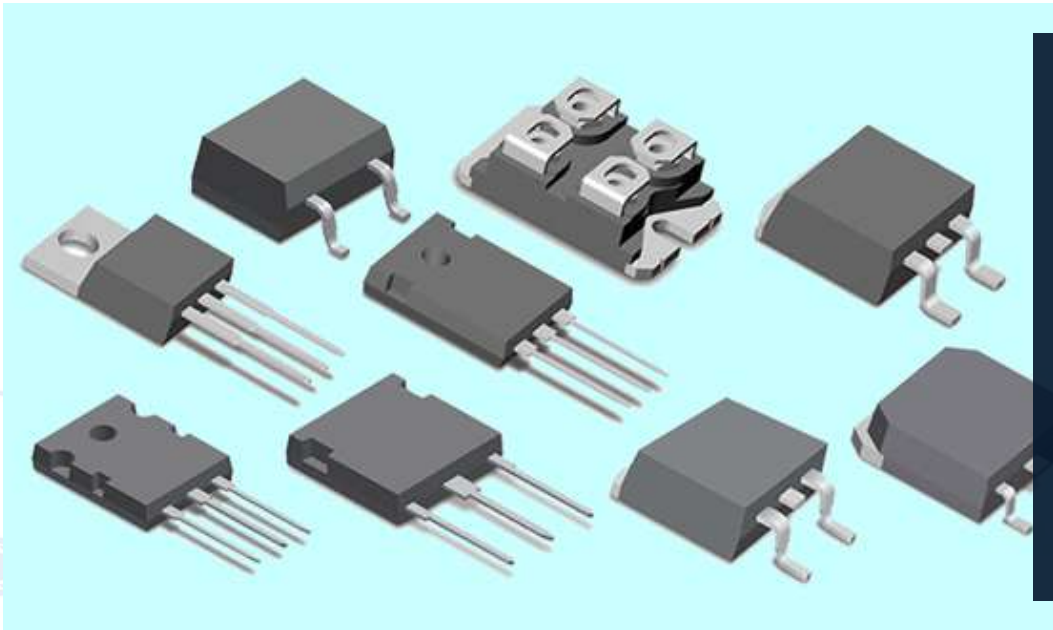
Poworld Electric Co., Ltd. was established in 1987, Specializing in the design and manufacturing of electrical test equipment for semiconductor devices. Our solutions cover power semiconductor devices, including diodes and rectifiers, backed by nearly 40 years of experience in semiconductor test equipment manufacturing.

02

Headquartered in Taiwan with a global vision, our products are marketed worldwide, serving customers across the United States, Europe, Southeast Asia, and mainland China. With reliable product quality and professional technical support, we are trusted by leading customers worldwide. Through continuous R&D investment and technological innovation, We have steadily established a leading position in the semiconductor test instrumentation industry.



# Semiconductor & Optoelectronic Device Test Solutions



- Diode
- MosFET
- SCR
- Triac
- IGBT
- Opto-Isolation
- Photo Sensing
- Driver Control

# Diode Test Solutions

Comprehensive Electrical Characterization

- Current Measurement : 1 nA → 100 A
- Voltage Measurement : 1 mV → 2.4 kV
- From small-signal devices to power modules, covering R&D, validation, and mass production

## 1 Small-Signal Device Testers

- Small Signal Diode Tester
- Schottky Diode Tester
- ESD Diode Tester  
600V/5A

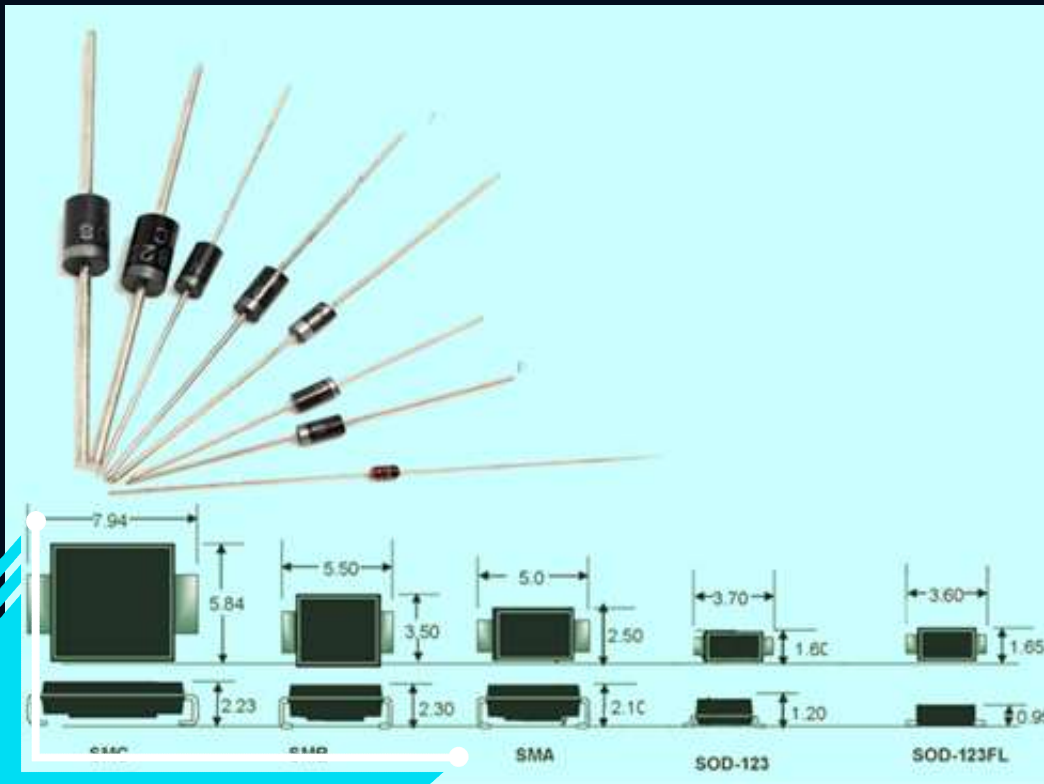
## 2 Power Device Testers

- Rectification Diode Tester
- TVS Diode
- High Voltage / High Current  
Tester (100A / 2000V)

## 3 Module Testers

- Diode Module Tester
- Bridge Rectifier Tester  
(1200A / 2400V)

# Diode Test Solutions



## Basic Electrical Characteristics Tester

- TVR6880A
- TVR6840B
- SZ6210S
- APT6004.



## DeltaVF Tester

- DVF6880
- DVF6600



## Thermal Resistance Test Equipment

- RTHJ6100D



## Other Test Equipment

- TVS Diode: VC6880, VC5498
- Schottky Diode: SSG6880
- Zener: ZZT6800B

# Three-terminal Device Test Solutions

Comprehensive Electrical Characterization

- Current Measurement: : 1 nA  $\rightarrow$  200 A
- Voltage Measurement : 1 mV  $\rightarrow$  2.4 kV
- From small-signal devices to power modules, covering R&D, validation, and mass production

## 1 Small-Signal Device Testers

- Parameter Tester  
(5A / 600V)

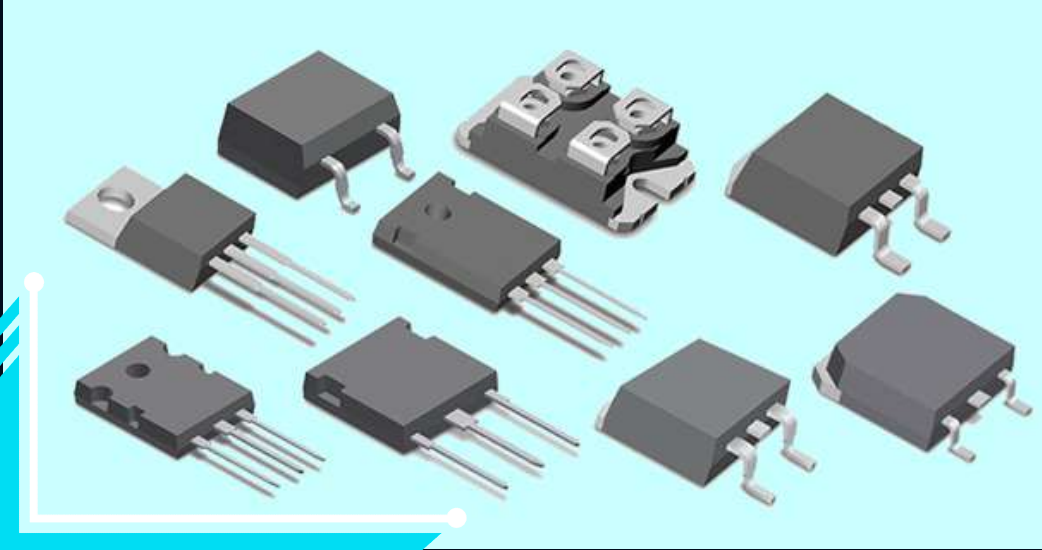
## 2 Power Device Testers

- Power MOSFET / SCR Tester  
(200A / 2400V)

## 3 Module Testers

- Power Module Tester
- IGBT / SCR Module Tester  
(1200A / 2400V)

# Three-terminal Device Test Solutions(MosFET Triac..)



## Basic Electrical Characteristics Tester

- RGT2100
- PFET8200G
- APT6004



## Ciss Crss Coss Rg Tester

- PCV1800



## Short - Circuit Emulator

- PSCE1600



## INDUCTIVE LOAD TESTER

- PER8220MD



## Forward Surge

- PIF1500A

# Optoelectronic Device Test Solutions

Dedicated Test Systems for Rapid Deployment

- Poworld integrates decades of test expertise directly into dedicated systems
- Eliminating complex development and setup
- Enabling fast learning curves and highly efficient, accurate testing of optoelectronic devices.

## 1 Opto-Isolation Testers

- Phototransistor Tester
- PhotoTRIAC Tester
- PhotoMos Tester
- GateDriver Tester
- High speed Coupler Tester

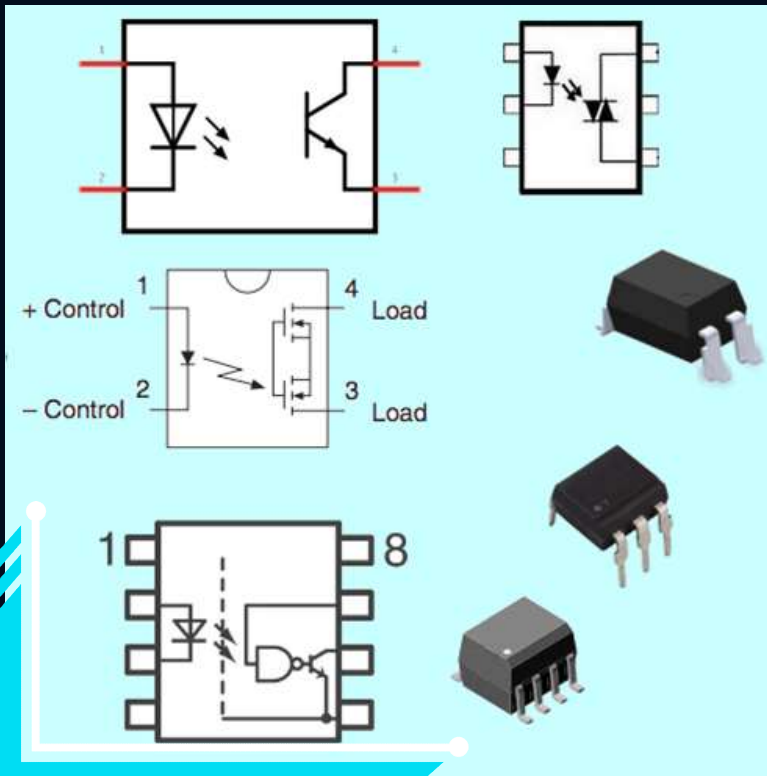
## 2 Photo Sensor / Photodiode Testers

- Photodiode Tester
- PhotoPV Tester
- PhotoSensor Tester

## 3 LED Testers

- ICled Tester
- Led Tester

# Optoelectronic Device Test Solutions



## OptoCoupler

- OPTO2817D
- APT6004E



## OptoMos

- OPTO2020M
- APT6004E



## High Speed Optocoupler

- OPTO13XD



## OPTOTRIAC

- OPTO29TP



## GateDriver

- OPTO13XD

# Solar Device Test Equipment

## Four-Station TMTT Photovoltaic Test System

Integrates DC, Reverse Surge, and  $\Delta V_F$  tests into one system for comprehensive and high-throughput photovoltaic diode testing.

DC Electrical Test  
VF,VB,IR Test

REVERSE SURGE TEST

$\Delta V_F$  Test

DC Electrical Test  
VF,VB,IR Test QC

# Four-Station TMTT Photovoltaic Test System



## Test Equipment

T1  
TS100JA  
(DC)

T2 SSG6050  
(Schottky Surge Tester)

T3 PDF8000P  
( $\Delta V_F$  Tester)

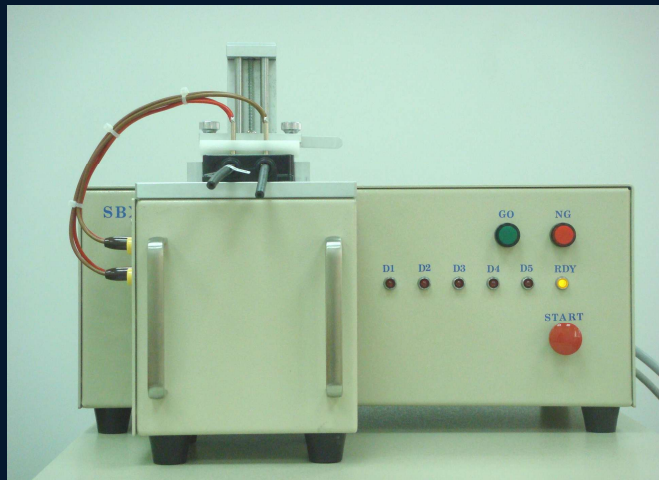
T4 TS100JA  
(DC Tester)



# TS100JA

## Multi-Function Diode Sorting Tester

- **DC TESTER**
- Voltage Output : 1 V → 400 V
- Current Measurement : 1 nA → 10mA
- Current Output : 1uA → 100A
- Voltage Measurement : 1 mV → 400V



**Specifically designed for solar panel bypass diodes**  
**Simultaneous measurement key parameters**  
**including VF, VBR, and IR.**



**Supports advanced test items:**  
**IR Surge, VB, ΔVR, IR%, IR1, IR2, and DIR.**



**Automatic polarity detection.**



**Suitable for production testing, incoming/outgoing**  
**inspection, R&D, and sample evaluation.**

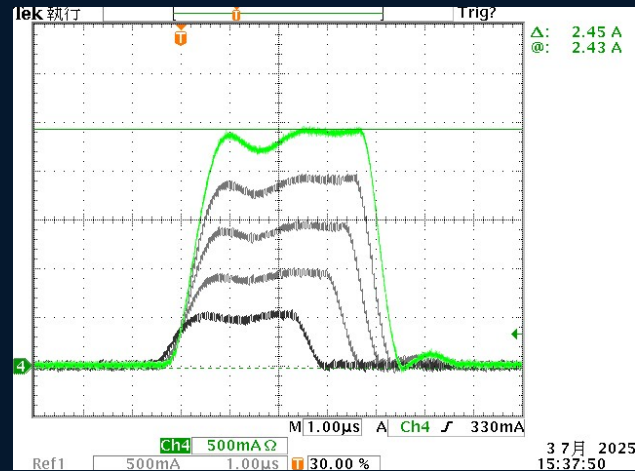


**Compatible with switch boxes for solar**  
**module electrical testing.**

# SSG6050

## SCHOTTKY DIODE REVERSE SURGE TESTER

- Current Output : 0.5A → 50 V
- Voltage Measurement : 5 V → 350 V
- PULSE WIDTH: 1  $\mu$ S ~ 100  $\mu$ S
- PERIOD: 100  $\mu$ S ~ 9999  $\mu$ S
- PULSE NO: 1 ~ 20.



**Dedicated to reverse surge testing of Schottky diodes**  
Used to evaluate the reliability of guard ring structures



**Supports multiple package types**  
with 11 built-in package selections



**Automatic polarity detection**

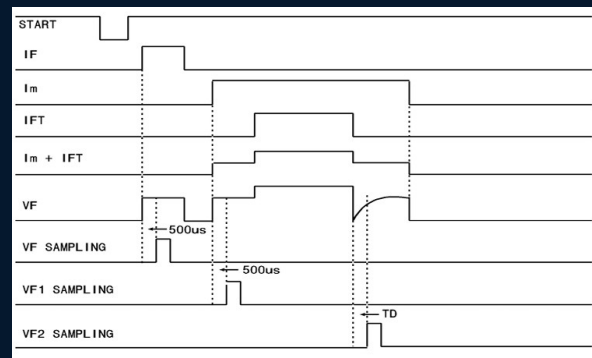


**Compatible with TMTT**  
handler

# PDF8000P

## $\Delta$ VF TESTER

- IF / IT Current Output : 10 A  $\rightarrow$  350 A
- Im Current Output : 1 mA  $\rightarrow$  100 mA
- Voltage Measurement : 1 mV  $\rightarrow$  4000 mV
- PW Time: 1mS  $\sim$  15 mS
- Td Time : 100 $\mu$ S  $\sim$  1000  $\mu$ S.



**Assessment of diode package soldering quality and thermal resistance (Rth) performance.**



**Supports multiple package types with 11 built-in package selections**



**Automatic polarity detection**



**Compatible with TMTT handler**

# MOSFET Test Solutions

## 4-Station TMTT Dual-Die Test System

The 4-station TMTT dual-die test system integrates DC, UIS, Rg, Ciss, Crss, and transient thermal resistance tests into a single platform, enabling comprehensive and high-efficiency MOSFET testing.

DC Electrical  
Test  
Transient Thermal  
Test

UIS Test  
Unclamped Inductive  
Switching Test

Capacitance Test

DC Electrical Test  
QC

# 4-Station TMTT Dual-Die Test System



## Test Equipment

T1 RGT2100  
(DC+ $\Delta$ VDS TESTER)  
+ MTRX

T2 PER8020MD  
(UIS Tester) + MTRX

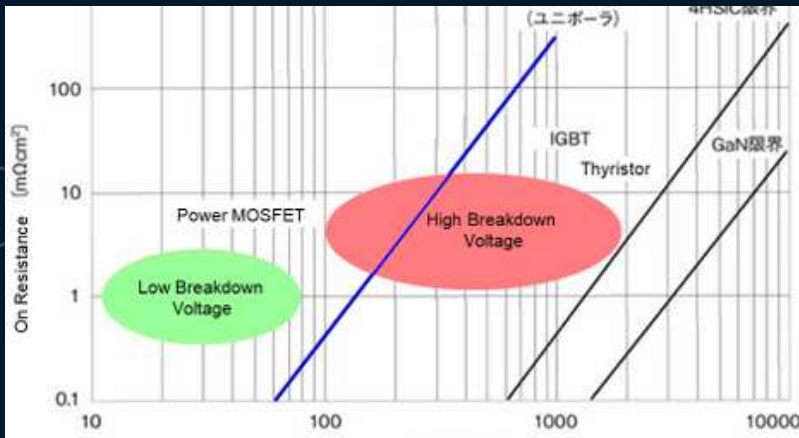
T3 P6635R  
(RG+Ciss Tester) +  
MTRX

T4 PFET8000G  
(DC Tester) +  
MTRX

# RGT2100

## Basic Semiconductor Electrical Testing

- DC+ $\Delta$  VDSTESTER
- Voltage Output : 1 V  $\rightarrow$  2000 V
- Current Measurement : 1 nA  $\rightarrow$  100 A
- Current Output : 1 $\mu$ A  $\rightarrow$  100A
- Voltage Measurement : 1mV  $\rightarrow$  2000V



**Built-in oscilloscope**



**Low on-resistance measurement**



**Software circuit response adjustment**



**MOSFET Transient Thermal Resistance Measurement**



**Device Categories:**

**Diode 、 MOSFET 、 TRIAC 、 SCR 、 Transistor**

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# RGT2100 Oscilloscope Function Overview

Built-in Oscilloscope & Waveform Analysis

The RGT2100 integrates an advanced oscilloscope and waveform analysis function, enabling real-time voltage and current waveform capture during measurement to enhance insight into device dynamic behavior and stability.

## Key Features & Benefits

- Real-time waveform capture and synchronous display
- Improved measurement stability and repeatability
- Optimized test timing configuration
- Reduced probe dependency and measurement errors
- Enhanced system safety and operational reliability
- Simplified test architecture and reduced system cost
- Suitable for R&D, validation, and mass production



# RGT2100 Response Compensation Function

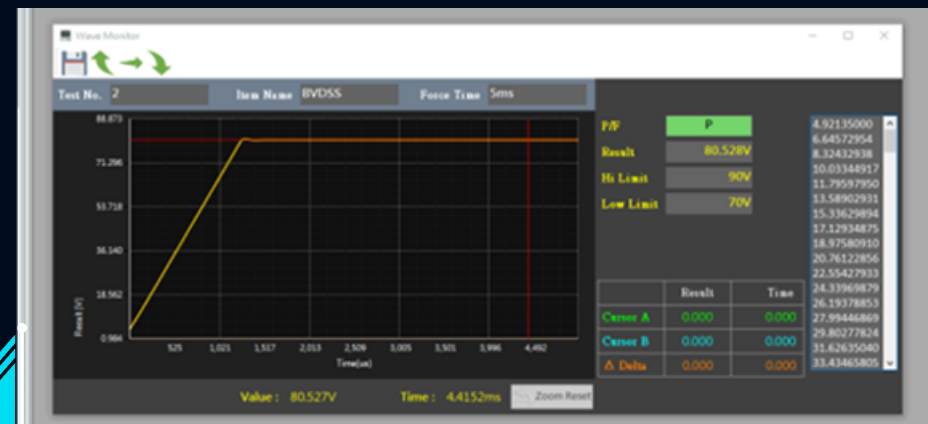
During testing, material response variations of the DUT may cause oscillations, resulting in unstable waveforms and unreliable measurement results.

The built-in compensation mechanism of the RGT2100 effectively suppresses oscillations, stabilizing waveforms and ensuring accurate and repeatable results.

## Before Compensation



## After Compensation

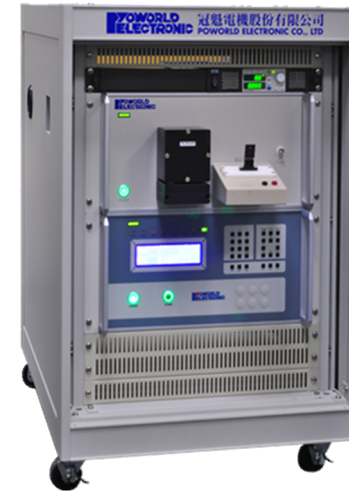
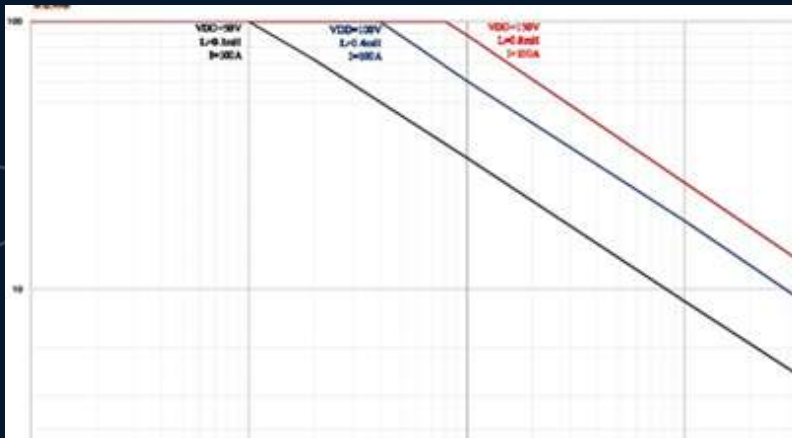


# PER8020MD

UIS Tester

(Unclamped Inductive Load Tester)

- Voltage Output (VD) : 40 V ~ 2500 V
- Current Output (IP) : 1 ~ 100 A
- Gate Voltage (VGS) : -20 V ~ +20 V
- DC Power Supply (VDD) : 150 V / 5 A
- td (Pulse Width) : 20  $\mu$ s ~ 500  $\mu$ s
- External Inductor Box (Optional): 10  $\mu$ H to 159.9 mH



**Compliant with MIL-STD-750C, Method 3470**



**Oscilloscope connection supported for observing test waveforms**



**Compatible with TMTT handler**



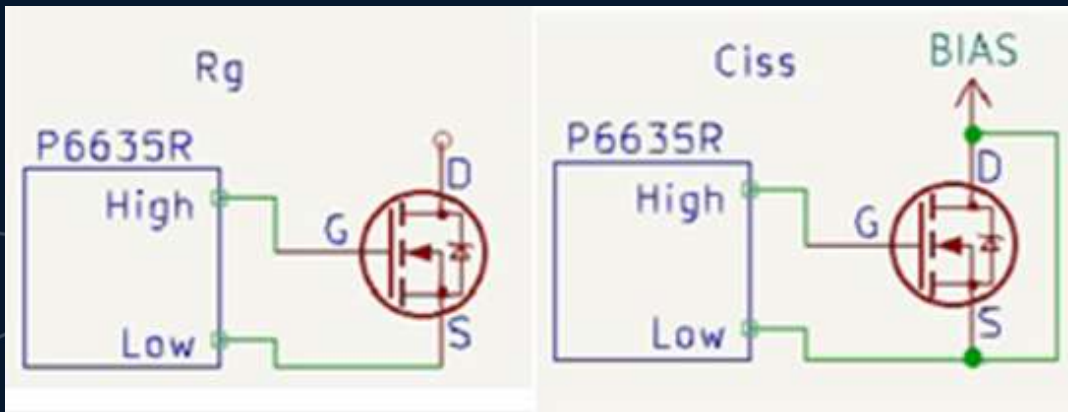
**Compatible with MOSFET switch box for diode testing (MOSFET provided by user)**

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# P6635R

MOSFET : R<sub>g</sub> 、 C<sub>iss</sub> 、 C<sub>rss</sub> 、 Diode : C<sub>j</sub> TESTER

- Measurement Frequency : 100K Hz → 1M Hz
- Bias Voltage Output : 0 V → 25 V
- Capacitance Range : 1 pF → 10 nF
- R<sub>g</sub> Measurement Range : 1 Ω → 1K Ω



**Built-in contact check function**



**Supports automated handler interface**



**R<sub>g</sub>, C<sub>iss</sub>, and C<sub>rss</sub> measured at the same station**

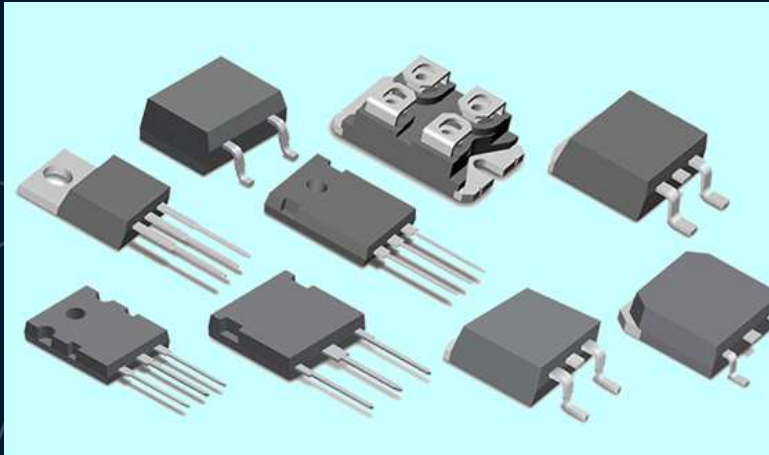


**Software supports parameter download and data acquisition**

# PFET8200G

## Basic Semiconductor Electrical Testing

- Voltage Output : 1 V  $\rightarrow$  2000 V
- Current Measurement : 1 nA  $\rightarrow$  10 mA
- Current Output : 1 $\mu$ A  $\rightarrow$  200A
- Voltage Measurement : 1 mV  $\rightarrow$  2000V
- Max VGS :  $\pm 30$ V.



**Supports measurement GaN and SiC device**



**Low on-resistance measurement**



**User-programmable test process**



**Optional curving software for BVDSS, IDSS, IGSSF plotting**

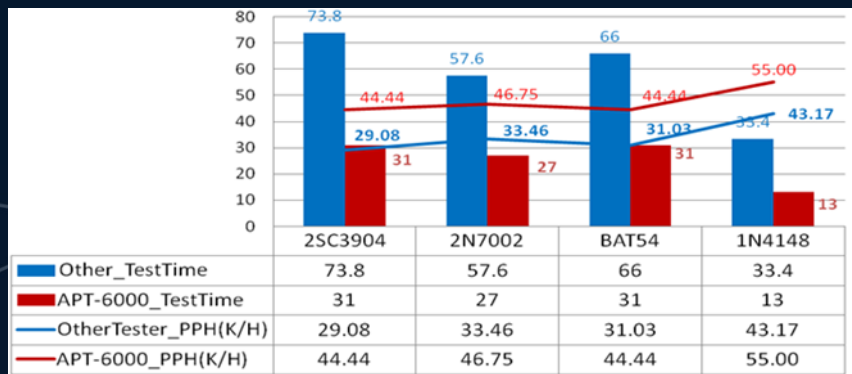


**Device Categories:**  
**Diode 、 MOSFET 、 IGBT 、 Transistor**

# APT6004

## Small-Signal Device Test System

- HV Source : 1 V  $\rightarrow$  600 V / 1 $\mu$ A~10mA
- Leakage Measure : 10pA~10mA
- HV Measure : 1 V  $\rightarrow$  600 V
- HC Source : 1 $\mu$ A  $\rightarrow$  5A
- HC Measure : 1 $\mu$ A~5A



**UPH:55K (Test Time=13mS Index Time=50mS)**



**Built-in oscilloscope**



**Expandable matrix supports 8-pin device testing**



**Parallel testing architecture significantly improves efficiency and reduces test cost**



**Device Categories:**  
Diode 、 MOSFET 、 Photo Couple 、 Transistor

# PM5300

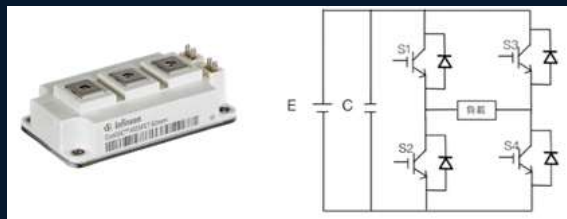
## Bridge Inverter Module Test Solution

### Maximum Ratings

- Max Voltage : 1000 V
- Max Current : 500A

### Test Item

- High Current test : RDSON 、 VFSD
- electrical parameters: VTH 、 IGSS 、 IDSS 、 BVDSS
- EAS Test (Optional): 100A/2500V or 300A/500V



**Supports Multi-Input / Multi-Output module testing**



**Built-in oscilloscope**



**User-programmable test sequences for flexible applications**



**integration with handlers for production testing**

# TVR5KM

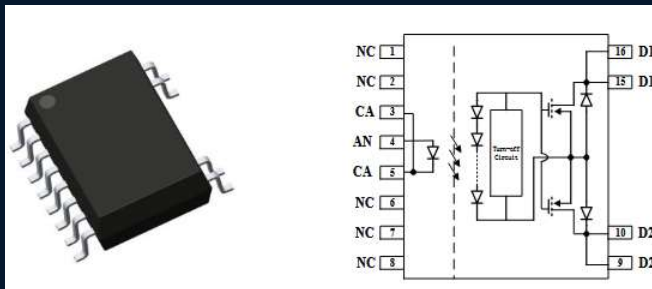
## HV TESTER for Diode & MOSFET

- Voltage Output : 800 V  $\rightarrow$  4999 V
- Current Measurement : 0.1  $\mu$ A  $\rightarrow$  800 $\mu$ A
- Current Output : 0.001mA  $\rightarrow$  1A
- Voltage Measurement : 1 mV  $\rightarrow$  4999V

Test Item:

Diode:VF,VB,IR

MosFET:IDSS,BVDSS



**Designed for high-voltage diodes and PhotoMOS devices**



**User-programmable test sequences for flexible applications**

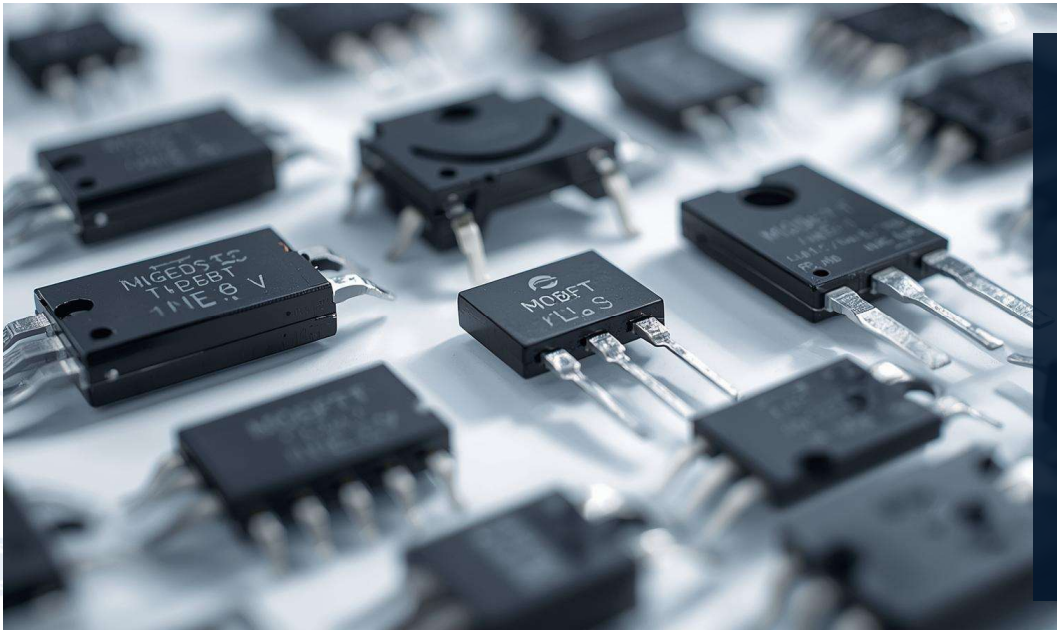


**Built-in yield analysis for quality monitoring**



**Integration with handlers for production testing**

# Laboratory Equipment



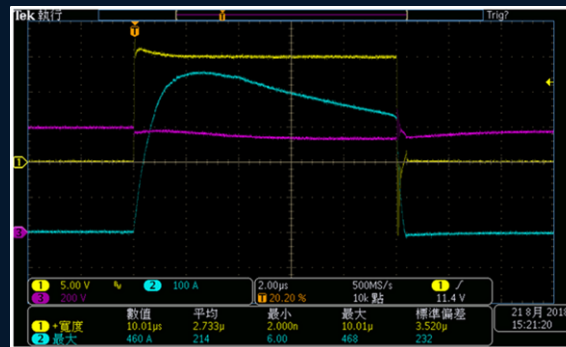
- Short-Circuit
- QRR Tester
- Ciss & Rg Tester
- High Current Tester
- HTRB/HTGB
- IOL
- Environment Chamber
- Test Socket
- 8-inch Wafer Prober

# PSCE1600

- Short-Circuit Emulator System Overview
- The Short-Circuit Emulator is designed to simulate short-circuit conditions of power devices such as IGBTs and MOSFETs in real applications, enabling evaluation of device robustness and reliability under extreme fault conditions.

## Specifications:

- Drain Voltage : +10V ~ +600V
- Gate Driver : +15V
- Pulse Duration : 1uS to 30uS
- MAX Current : 800A



**Built-in oscilloscope**



**Simplified operation for improved system reliability.**



**Safety Cover Interlock Protection**

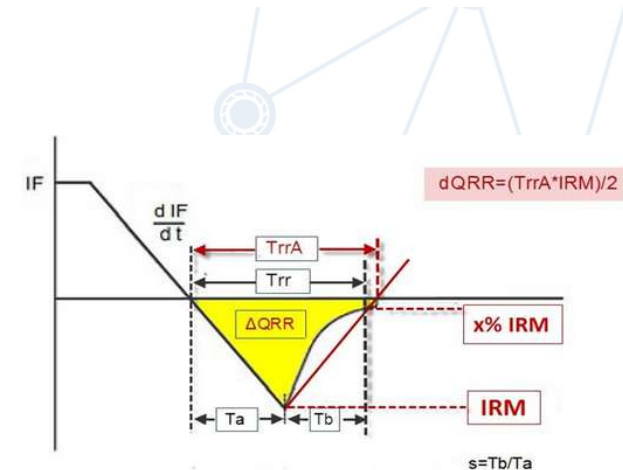


**Automated Report Generation**

# PQRR6885

- QRR test measures reverse recovery charge and current spikes during device turn-off.
- Specifications
  - IF (Forward Current) : 1A ~ 50A  $\pm$  10%
  - **IRM(Reverse Current) : 30A MAX**
  - **VR(Reverse Voltage) : 30V/50V/100V/200V/400V**
  - **dIF/dt : 50A/ $\mu$ S ~ 500 A/ $\mu$ S , Step 5A .**
  - **TRR / TRRA : 10nS-2 $\mu$ S**

Qrr 測試用於評估功率元件在反向恢復過程中的電荷量，以判斷其切換損耗、高頻性能與系統可靠度。  
 Qrr testing evaluates the reverse recovery charge of power devices, to assess switching losses, high-frequency performance, and system reliability.



**Configurable Current Slow Rate(Di/Dt)**



**IRM, Tr, TrrA, and  $\Delta$ QRR can be measured without an external oscilloscope**



**Oscilloscope Integration**



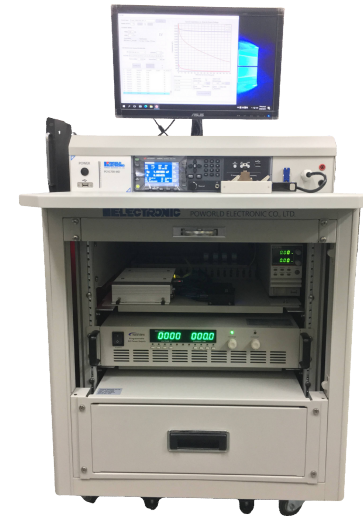
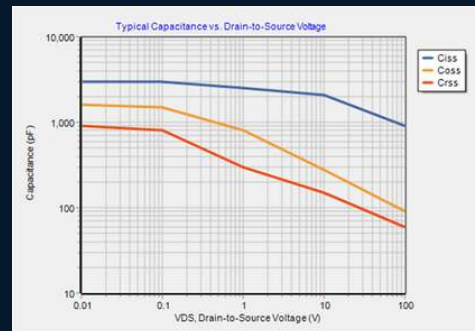
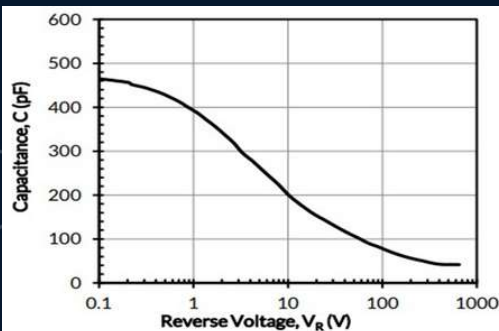
**Automated Report Generation**



**Oven Integration**

# PCV1800

- MOSFET Capacitance and Gate Resistance Measurement
- Measures  $C_{iss}$ ,  $C_{oss}$ ,  $C_{rss}$ , and  $R_g$  of both N-type and P-type MOSFETs, providing comprehensive device characterization for R&D and QA applications.
- Supports bias voltage and frequency configuration with automatic C-V curve plotting.
- Specifications
  - Bias Voltage : 0V~1700V
  - Test Frequencies : 100K Hz ~ 1 MHz
  - Capacitance measuring range : 0.1 pF~10 nF
  - Resistance measuring range : 0.1  $\Omega$  – 1 k $\Omega$



**Automatic Stability Check:**



**Automated Graphing & Report Generation**



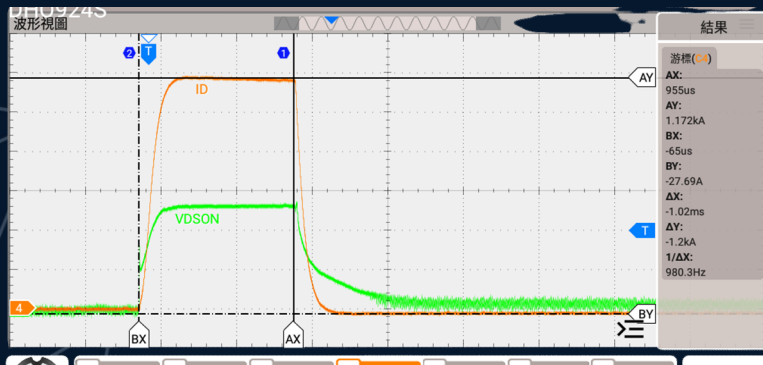
**Automated Report Generation**



**Easy Operation**

# PVF1200A

- PVF1200A High-Current Test System
- PVF1200A is designed for third-generation semiconductor devices, offering up to 1200A current capability, ideal for testing high-power SiC MOSFETs, IGBTs, and diodes in R&D, QA, and production environments.
- Specifications:
  - $I_D$  : 10A~1200A
  - $V_{DS}$  : 0~20V
  - $V_{GS}$  : -20V~+20V
  - **Device Categories**
    - Diode 、 MOSFET 、 IGBT 、



**Flexible Pulse Width: 500uS~1000uS**



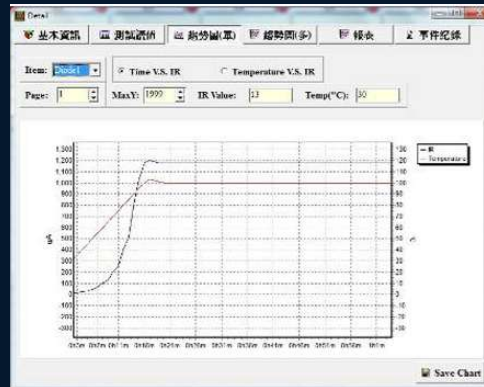
**Manual and Automated Operation**



**Advanced Data Acquisition**

# HTRB / HTGB

- This test applies reverse bias under high-temperature conditions to accelerate evaluation of leakage current stability, junction reliability, and insulation robustness under long-term high electric field stress.
- Standards:
  - JEDEC JESD22-A108 (HTGB)
  - JEDEC JESD22-A101
- Specifications:
  - IR Range : 0.01uA~200mA
  - Test Devices: Diode 、 MOSFET
  - Test item : IR 、 IDSS 、 IGSS



**Real-Time Current and Temperature Monitoring(minute)**



**Multi-Device Testing(80 Devices)**



**Device Behavior Analysis**



**Automatic Anomaly Logging**

# H3TRB

- H3TRB 烤箱設備主要設計用於執行「高溫高濕反向偏壓」測試，旨在模擬嚴苛環境下半導體元件的可靠性。
- 規範：
  - JEDEC JESD22-A101
  - AEC-Q101
- Specifications:
  - IR Range : 0.01uA~200mA
  - Test Devices : Diode 、
  - Test item : IR 、



**Real-Time Current and Temperature Monitoring(minute)**



**Multi-Device Testing(80 Devices)**



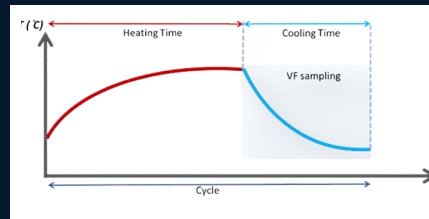
**Device Behavior Analysis**



**異常自動記錄  
Automatic Anomaly Logging**

# PIOL-80

- IOL ( Intermittent Operational Life ) Test
- The IOL test simulates switching operation through temperature cycling, focusing on thermal stress at contact interfaces and high-temperature regions to estimate power MOSFET lifetime and reliability.
- Standard:
  - MIL-STD-750D METHOD 1037.2
- Specifications:
  - Sets: 10 sets
  - Device count: A set per 80 devices
  - VDS: +5v to +20v  $\pm 5\%$
  - IDS: +0.5A to +4A  $\pm 5\%$
  - Im: +10mA
  - Power: 2.5w to 40w
  - Heating time: 1 to 300 sec
  - Cooling time: 1 to 300 sec
  - Cycles: 20000 times maximum
  - Power Supply: 360w(30v/36A)
  - DUT Type: N-Channel MOSFETs, IGBTs
  - DUT Package: TO-263-7L 、 TO-247-3L 、 TO-247-4L



**Constant-Power Heating**



**VFSD Measurement allows verification of the junction temperature**



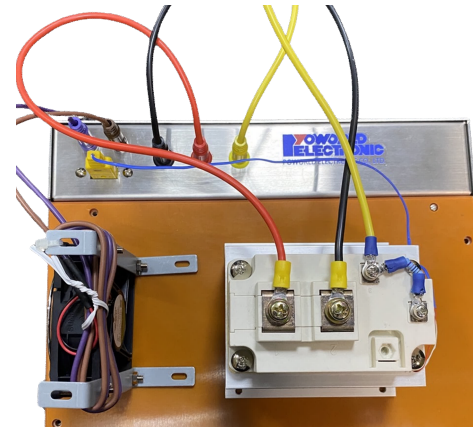
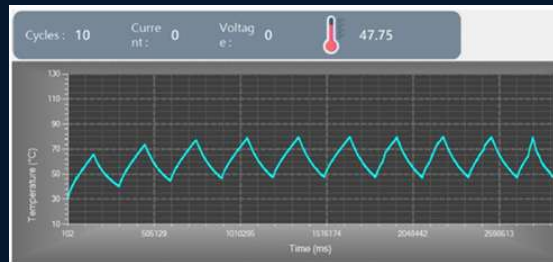
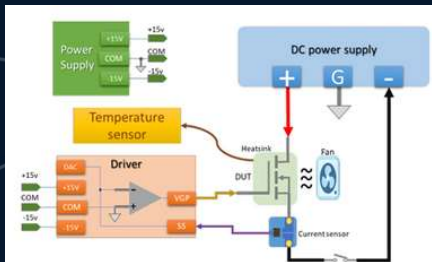
**Automatic Anomaly Logging**



**Advanced Data Acquisition**

# PIOL-2040KIT

- IOL ( Intermittent Operational Life ) Test
- Standard:
  - MIL-STD-750D METHOD 1037.2
- Specifications:
  - ON Time: : 5 mins Maximum
  - OFF Time: 5 mins Maximum
  - DUT Power: 360W
  - Cycles: : 20000 Maximum (Times)
  - DUT Type N-Channel MOSFETs,IGBTs
  - C Temperature Sensor Range: Room Temperature(25°C) ~ 150°C



**Constant-Power Heating**



**Automatic Anomaly Logging**



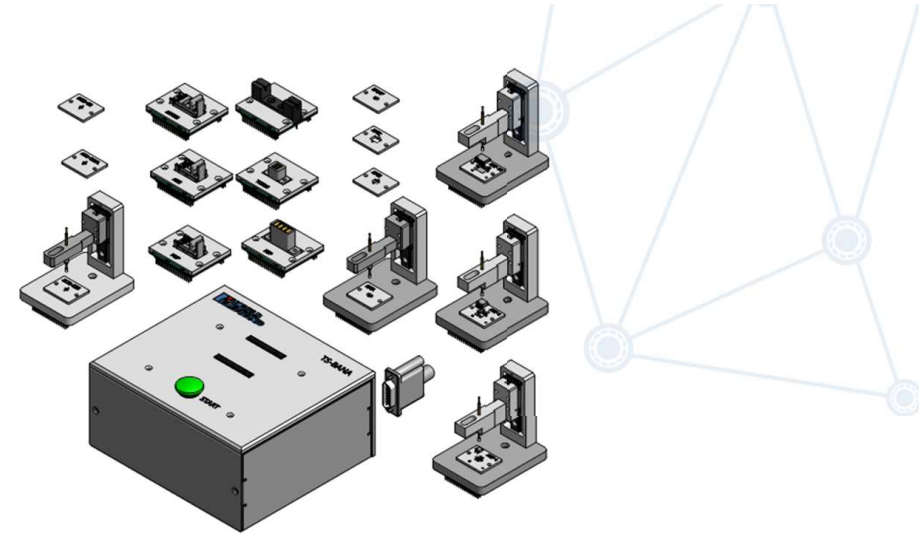
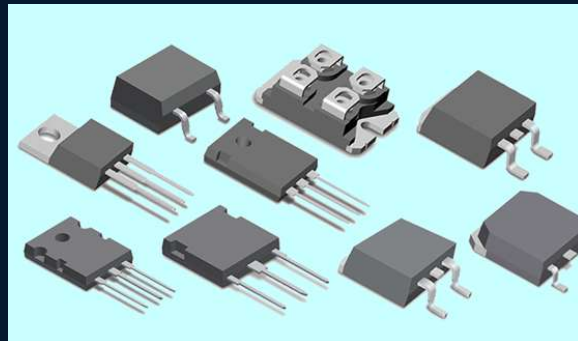
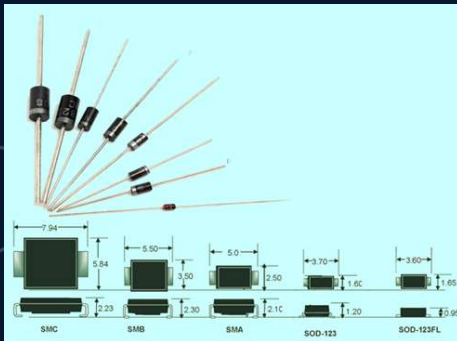
**Portable and User-Friendly**



**Advanced Data Acquisition**

# TS Test Socket

- Modular change kits allow flexible and rapid integration of electrical testing for various package types.
- Supported Packages:
  - AXIAL 、 TO-220
  - SMA,SMB,SMC, SMAF
  - SOD80,SOD123, SOD123F 、 SOT23-3
  - MBF 、 ABS 、 KBP
  - SOP4 、 SOP6 、 SOP16



**Modular Design**



**Multi-Package Support**



**Accurate Electrical Characterization**



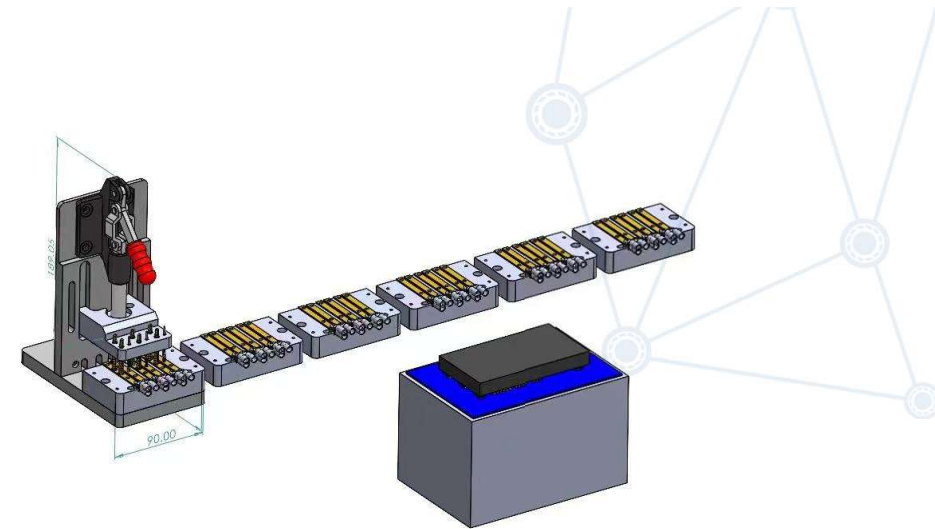
**Easy Operation**



**High Flexibility**

# Modular Test Fixtures

- Custom-designed fixtures tailored to various package types, compatible with multiple testers for accurate electrical characterization in R&D and QA.
- Supported Devices:
  - IGBT
  - MOSFET
  - SCR
  - BRIDGE RECTIFIER
  - DIODE



**Customized Design**



**Multi-Package Support**



**Accurate Electrical Characterization**



**Low and Stable Contact Resistance**



**Easy Operation**

# BC-02 Thermal Chamber

- The BC-02 is an electrical test system designed for material heating experiments. Equipped with a highly reliable temperature control system, it simulates electrical characteristic variations from room temperature up to 150°C, making it ideal for R&D validation and material analysis applications.
- Specifications :
  - External Dimensions : 200L \* 300W \* 160H (m/m)
  - Internal Chamber Size : 45(L) \* 100(W) \* 40(H) (m/m)
  - Weight : 7kgs
  - Operating Temperature: Room Temperature ~ 150°C (max)



**High-Reliability Temperature Control**



**Flexible Fixture Compatibility**



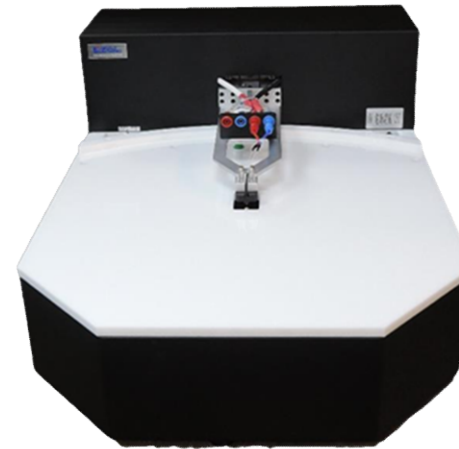
**Integrated Electrical Measurement**



**R&D and Material Analysis Oriented**

# 8-Inch Wafer Prober

- This semi-automatic wafer prober is designed for wafers up to 8 inches in diameter.
- It features PLC-based control and a dial-type adjustment interface, enabling precise control of probe contact depth and force to prevent wafer damage.
- The system supports both manual operation and foot-switch control, enhancing operational convenience and stability for R&D and wafer-level electrical testing.
- Operation :
  - Manual operation / Foot-switch control
- Probe Configuration :
  - 48–60 mil (Single probe)
  - 60–100 mil (Dual probe)
  - 100–160 mil (Dual probe)



**Supports Wafers up to 8 Inches**



**PLC Precision Control**

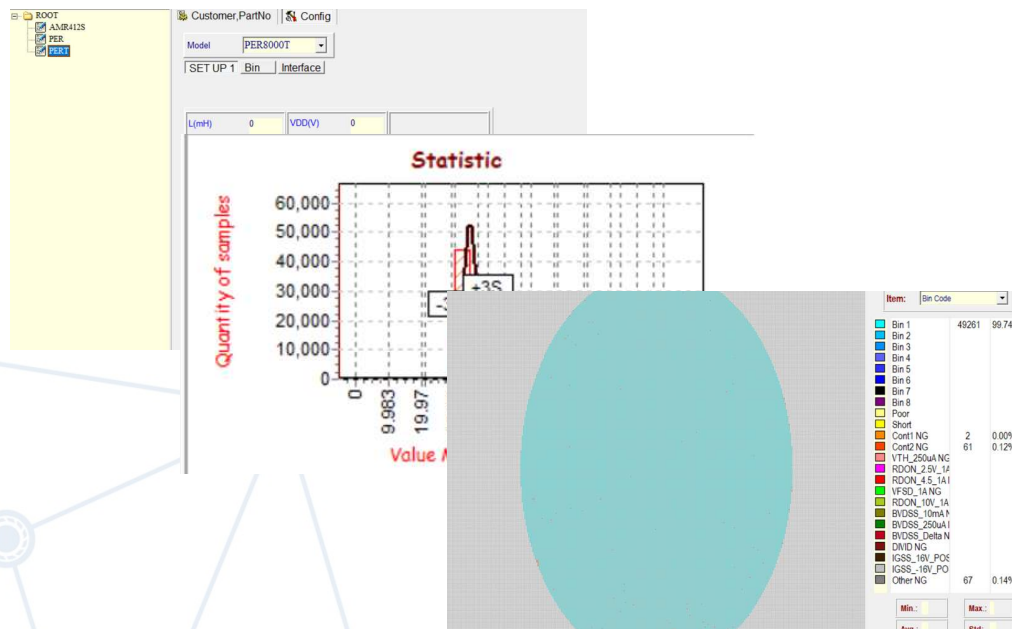


**Adjustable Probe Force**



**Semi-Automatic Operation**

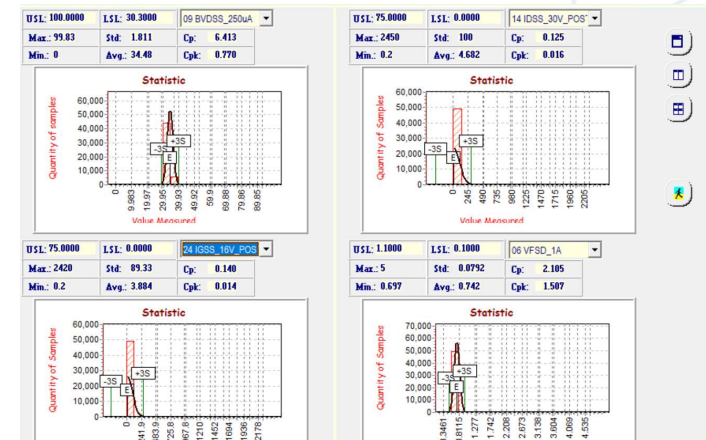
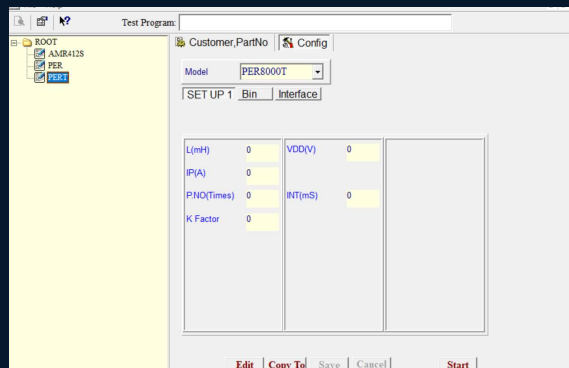
# Integrated Test Software Platform



- Our test software is independently developed to seamlessly integrate a wide range of test equipment, enhancing overall system performance and application flexibility.
- Through Poworld software solutions, enterprises can achieve smart manufacturing, improve efficiency, reduce costs, and accelerate digital transformation.

# PWPGMONO Data Acquisition Software

- Integration with Poworld Testers :
  - Centralized management of multiple testers for simplified operation.
- Real-Time Data Acquisition :
  - Automatically records every test result with complete data retention.
- Test Program Management :
  - Predefined and reusable test programs to reduce operator errors.
- Analysis & Reporting :
  - Comprehensive data analysis with yield and trend monitoring.
- Report Export :
  - Reports can be generated and exported for R&D and QA applications.



**Standalone Operation**



**Test Program File Management**



**Real-Time Data Acquisition and Storage**



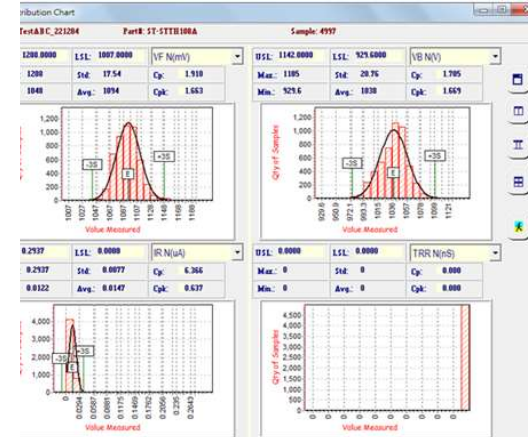
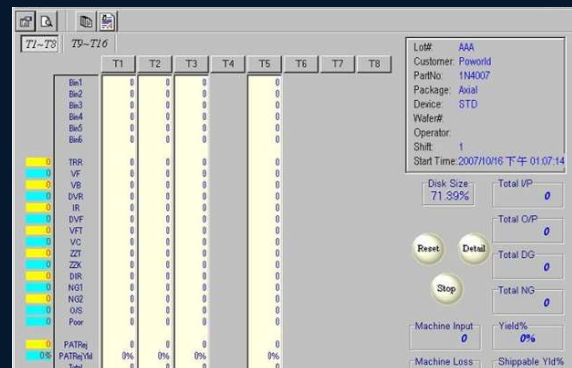
**GO / NG Statistics Display**



**Multi-Task Test Architecture**

# PW2007 Automated Production Management System

- PW2007 is a multi-tester automated test management and data acquisition platform designed for semiconductor production lines. It integrates multiple Kuan-Kuei testers and automation systems to centrally manage the entire production line.
- The system supports test program management, real-time data acquisition, centralized data storage, and remote monitoring, effectively reducing human error and improving mass production efficiency.



**Faster, More Accurate, and More Reliable Production Testing**



**Test Program File Management**



**Simplified operational workflow design to reduce the risk of error. Supports barcode scanner integration to effectively prevent human operation errors.**



**Intelligent process control. Supports Dynamic PAT Limits as well as SYL / SBL control mechanisms.**



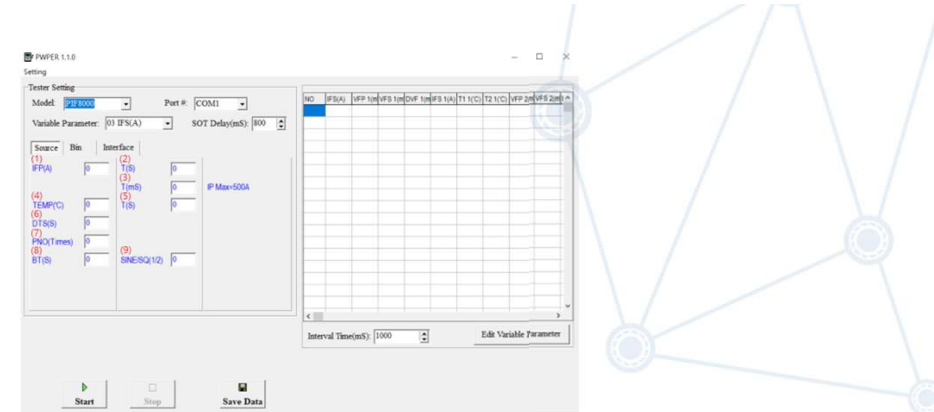
**Real-time remote monitoring. Enables remote monitoring across different locations**

**POWORLD ELECTRONIC**

# PWPER Engineering Capability Evaluation Software

- PWPER is a dedicated platform for evaluating material surge endurance, suitable for R&D validation, reliability assessment, and quality assurance applications.
- The system is compatible with multiple Poworld surge testers and provides flexible test modes with comprehensive data storage to accurately evaluate material robustness.

| A  | B     | C      | D      | E      | F      | G      | H      | I | J | K | L | M | N | O | P | Q | R | S | T | U | V |
|----|-------|--------|--------|--------|--------|--------|--------|---|---|---|---|---|---|---|---|---|---|---|---|---|---|
| 1  | VC NV | IP NA  | VC NV  | VC NV  | VC NV  | VC NV  | VC NV  |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 2  | 139   | 33.625 | 129    | 115.51 | 34.521 | 129.72 | 115.63 |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 3  | 141.9 | 34.141 | 141.77 | 114.99 | 35.099 | 141.29 | 114.47 |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 4  | 154.6 | 34.639 | 154.57 | 114.08 | 35.653 | 154.25 | 113.92 |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 5  | 167.7 | 35.122 | 167.27 | 113.86 | 36.18  | 167.18 | 113.44 |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 6  | 180.6 | 35.6   | 180.17 | 113.28 | 36.681 | 180.95 | 113.25 |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 7  | 193.5 | 36.055 | 193.19 | 112.79 | 37.199 | 193.3  | 112.79 |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 8  | 206.4 | 11.189 | 206.02 | 112.4  | 0      | 0      | 0      |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 9  | 219.3 | 0      | 0      | 0      | 0      | 0      | 0      |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 10 | 232.2 | 0      | 0      | 0      | 0      | 0      | 0      |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 11 | 245.1 | 0      | 0      | 0      | 0      | 0      | 0      |   |   |   |   |   |   |   |   |   |   |   |   |   |   |
| 12 | 258   | 0      | 0      | 0      | 0      | 0      | 0      |   |   |   |   |   |   |   |   |   |   |   |   |   |   |



**Supported Testers :UIS 、 Forward Surge 、 Schottky Surge 、 8/20 & 10/1000 Surge Testers**



**Dual Test Modes:  
Single surge current mode  
Step-increasing surge current mode**



**Optional integration with electrical testers  
for basic parameter measurement**



**Test data exportable to Excel format**

# Our Customers



# 學界交流



台灣大學  
**National Taiwan University (NTU)**



清華大學  
**National Tsing Hua University (NTHU)**



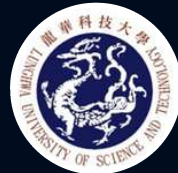
陽明交大  
**National Yang Ming Chiao Tung University (NYCU)**



中山大學  
**National Sun Yat-sen University (NSYSU)**



山東大學（中國）  
**Shandong University(Chiana)**



龍華科技大學  
**Lunghwa University of Science and Technology (LHU)**



明新科技大學  
**Minghsin University of Science and Technology (MUST)**



**Shanmugha Arts, Science, Technology & Research Academy(India)**



長庚大學  
**Chang Gung University (CGU)**

# Our Commitment

**We provide comprehensive services to help customers overcome technical and application challenges. Driven by continuous innovation and improvement, Poworld is deeply committed to third-generation semiconductor technologies, including SiC and GaN, working closely with customers to create long-term value and sustainable growth.**

# The End.

Thank You for Your Attention !!!

For any questions, please feel free to contact us.

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